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## N-Channel 650V (D-S) Super Junction Power MOSFET

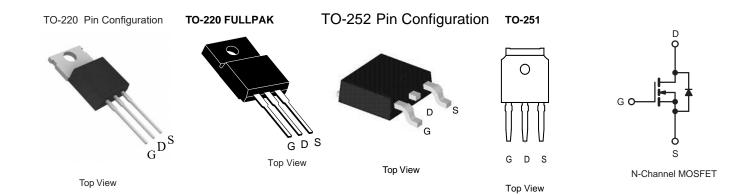
PRODUCT SUMMARY			
V <sub>DS</sub> (V)	650		
$R_{DS(on)}\left(\Omega\right)$	V <sub>GS</sub> = 10 V	2.3	
Q <sub>g</sub> (Max.) (nC)	31		
Q <sub>gs</sub> (nC)	4.6		
Q <sub>gd</sub> (nC)	17		
Configuration	Single		

#### **FEATURES**

- · Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s;



- Sink to Lead Creepage Distance = 4.8 mm
- · Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available



<b>ABSOLUTE MAXIMUM RATINGS</b> T	<sub>C</sub> = 25 °C, u	nless otherv	vise noted		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			$V_{DS}$	650	V
Gate-Source Voltage			$V_{GS}$	± 20	
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	- I <sub>D</sub>	2.0	
		T <sub>C</sub> = 100 °C		1.6	Α
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	10	
Linear Derating Factor				0.28	W/°C
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	250	mJ
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	1.5	А
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	3.5	mJ
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		$P_{D}$	35	W
Peak Diode Recovery dV/dtc			dV/dt	3.0	V/ns
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 <sub>q</sub>	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in
				1.1	N · m

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 73 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AS}$  = 1.5 A (see fig. 12).
- c.  $I_{SD} \le 1.6$  A,  $dI/dt \le 60$  A/ $\mu$ s,  $V_{DD} \le V_{DS}$ ,  $T_J \le 150$  °C.
- d. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	3.6	C/VV	

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static		•					
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub>	650	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	-	0.62	-	V/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ± 20 V		-	-	± 100	nA
Zana Onto Wallana D. C. C.		V <sub>DS</sub> =	V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V		-	100	,
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 480 \	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	500	μΑ
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 1.5 A <sup>b</sup>	-	2.3	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> :	= 50 V, I <sub>D</sub> = 1.5 A <sup>b</sup>	2.2	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V,		-	660	-	_
Output Capacitance	C <sub>oss</sub>	1 .	$V_{DS} = 25 \text{ V},$		86	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5		-	19	-	pF
Drain to Sink Capacitance	С		f = 1.0 MHz	-	12	-	
Total Gate Charge	Qg		I <sub>D</sub> = 1.6 A, V <sub>DS</sub> = 360 V, see fig. 6 and 13 <sup>b</sup>	-	-	31	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		-	-	4.6	
Gate-Drain Charge	Q <sub>gd</sub>	1		-	-	17	
Turn-On Delay Time	t <sub>d(on)</sub>			-	11	-	
Rise Time	t <sub>r</sub>	$V_{DD} = 300 \text{ V, } I_{D} = 1.6 \text{ A,}$ $R_{G} = 12 \Omega, R_{D} = 82 \Omega,$ see fig. $10^{b}$		-	13	-	- ns
Turn-Off Delay Time	t <sub>d(off)</sub>			-	35	-	
Fall Time	t <sub>f</sub>			-	14	-	
Internal Drain Inductance	$L_{D}$	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s	•					•
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	2.0	Α
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	10	^
Body Diode Voltage	$V_{SD}$	$T_J = 25  ^{\circ}\text{C},  I_S = 1.5  \text{A},  V_{GS} = 0  \text{V}^{\text{b}}$		-	-	1.6	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 1.6 A, dI/dt = 100 A/μs <sup>b</sup>		-	400	810	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	2.1	4.2	μС
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )					_D)

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300  $\mu$ s; duty cycle  $\leq$  2 %.



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#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

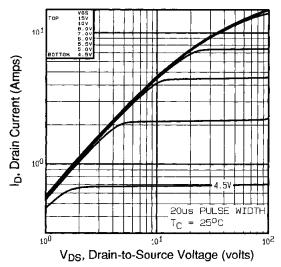


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

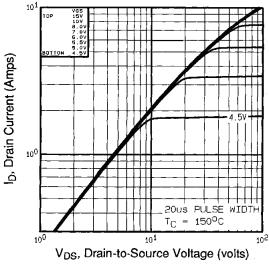


Fig. 2 - Typical Output Characteristics,  $T_C = 150$  °C

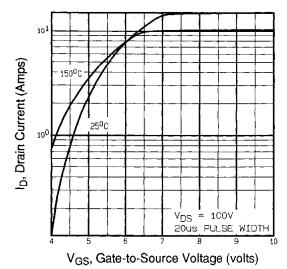


Fig. 3 - Typical Transfer Characteristics

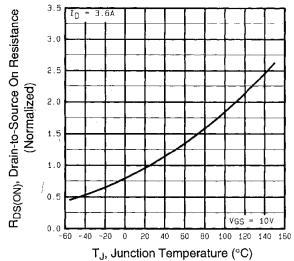


Fig. 4 - Normalized On-Resistance vs. Temperature



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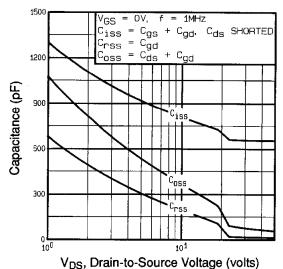


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

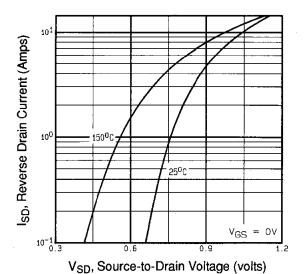


Fig. 7 - Typical Source-Drain Diode Forward Voltage

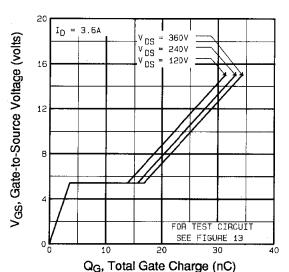
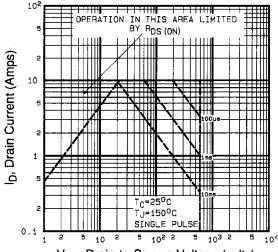


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



V<sub>DS</sub>, Drain-to-Source Voltage (volts) Fig. 8 - Maximum Safe Operating Area



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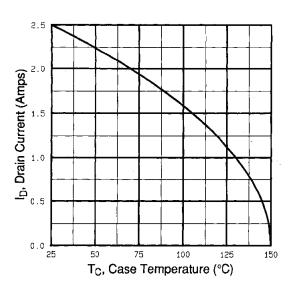


Fig. 9 - Maximum Drain Current vs. Case Temperature

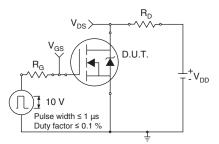


Fig. 10a - Switching Time Test Circuit

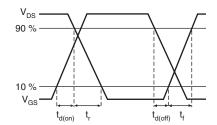


Fig. 10b - Switching Time Waveforms

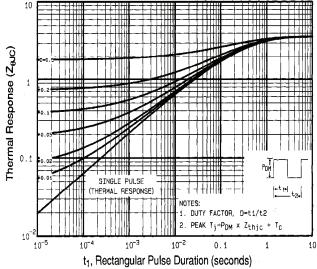


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

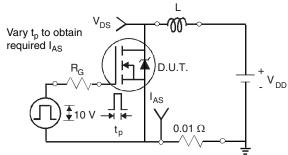


Fig. 12a - Unclamped Inductive Test Circuit

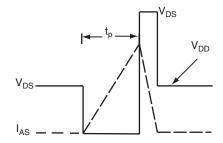


Fig. 12b - Unclamped Inductive Waveforms

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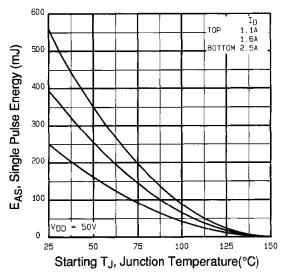


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

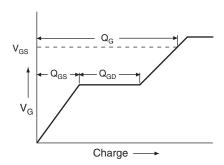


Fig. 13a - Basic Gate Charge Waveform

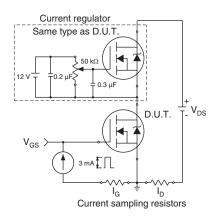
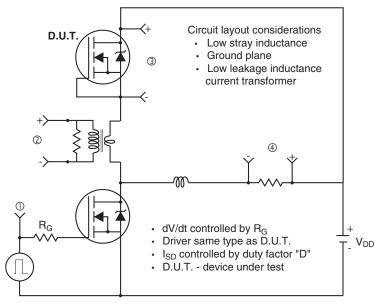
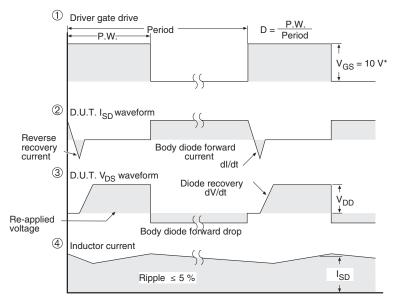


Fig. 13b - Gate Charge Test Circuit

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### Peak Diode Recovery dV/dt Test Circuit





\* V<sub>GS</sub> = 5 V for logic level devices and 3 V drive devices

Fig. 14 - For N-Channel





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